

Notice of References Cited		Application/Control No. 10/665,772	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
		Examiner JEONG S. PARK	Art Unit 2454	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2001/0034586	10-2001	Ewert et al.	702/188
*	B US-6,330,621	12-2001	Bakke et al.	710/5
*	C US-6,128,644	10-2000	Nozaki, Hideki	709/203
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.